

20A, 500V N-CHANNEL MOSFET

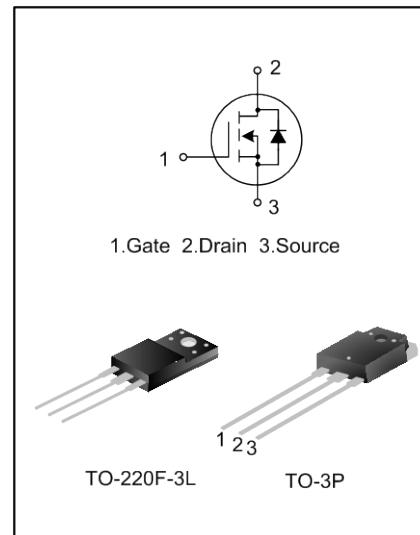
GENERAL DESCRIPTION

SVF20N50F/PN is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary F-Cell™ structure VDMOS technology. The improved planar stripe cell and the improved guard ring terminal have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

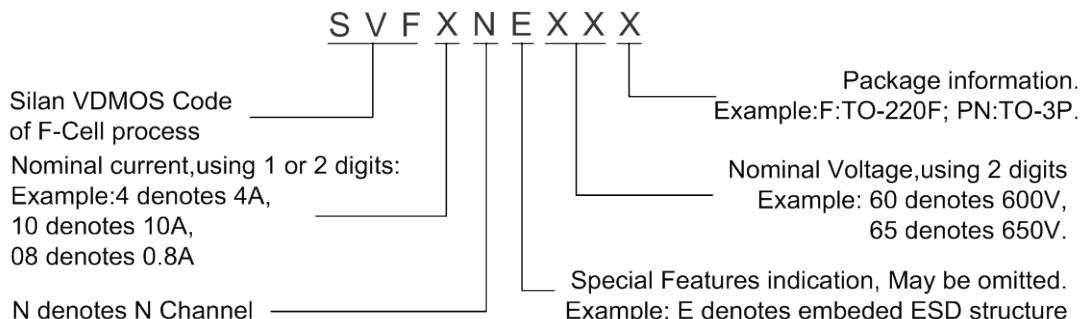
These devices are widely used in AC-DC power suppliers, DC-DC converters and H-bridge PWM motor drivers.

FEATURES

- ◆ 20A,500V, $R_{DS(on)(typ.)}=0.20\Omega @ V_{GS}=10V$
- ◆ Low gate charge
- ◆ Low Crss
- ◆ Fast switching
- ◆ Improved dv/dt capability



NOMENCLATURE



ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SVF20N50F	TO-220F-3L	SVF20N50F	Pb free	Tube
SVF20N50PN	TO-3P	20N50	Pb free	Tube



ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$ unless otherwise noted)

Characteristics	Symbol	Ratings		Unit
		SVF20N50F	SVF20N50PN	
Drain-Source Voltage	V_{DS}	500		V
Gate-Source Voltage	V_{GS}	± 30		V
Drain Current	I_D	20.0		A
		12.6		
Drain Current Pulsed	I_{DM}	80.0		A
Power Dissipation($T_c=25^\circ\text{C}$) -Derate above 25°C	P_D	72	252	W
		0.58	2.02	W/ $^\circ\text{C}$
Single Pulsed Avalanche Energy(Note 1)	E_{AS}	1596		mJ
Operation Junction Temperature Range	T_J	-55~+150		$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-55~+150		$^\circ\text{C}$

THERMAL CHARACTERISTICS

Characteristics	Symbol	Ratings		Unit
		SVF20N50F	SVF20N50PN	
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.74	0.50	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5	50	$^\circ\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS ($T_c=25^\circ\text{C}$ unless otherwise noted)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	B_{VDS}	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	500	--	--	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=500\text{V}$, $V_{GS}=0\text{V}$	--	--	1.0	μA
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 30\text{V}$, $V_{DS}=0\text{V}$	--	--	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}$, $I_D=250\mu\text{A}$	2.0	--	4.0	V
Static Drain- Source On State Resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}$, $I_D=10.0\text{A}$	--	0.20	0.27	Ω
Input Capacitance	C_{iss}	$V_{DS}=25\text{V}$, $V_{GS}=0\text{V}$, $f=1.0\text{MHz}$	--	2687.7	--	pF
Output Capacitance	C_{oss}		--	355.0	--	
Reverse Transfer Capacitance	C_{rss}		--	10.3	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=250\text{V}$, $I_D=20.0\text{A}$, $R_G=10\Omega$, (Note 2,3)	--	27.2	--	ns
Turn-on Rise Time	t_r		--	47.5	--	
Turn-off Delay Time	$t_{d(off)}$		--	78.7	--	
Turn-off Fall Time	t_f		--	41.1	--	
Total Gate Charge	Q_g	$V_{DS}=400\text{V}$, $I_D=20.0\text{A}$, $V_{GS}=10\text{V}$, (Note 2,3)	--	49.50	--	nC
Gate-Source Charge	Q_{gs}		--	14.28	--	
Gate-Drain Charge	Q_{gd}		--	16.95	--	



SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

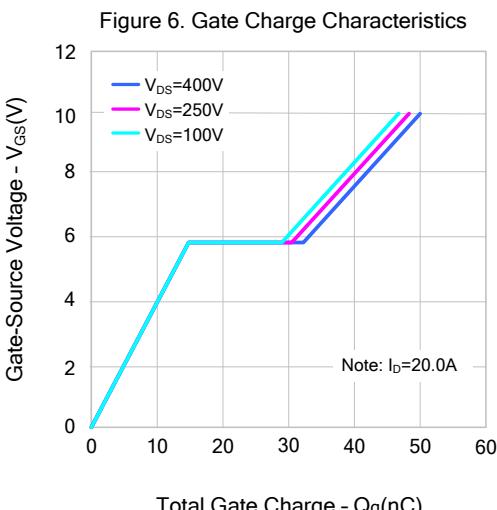
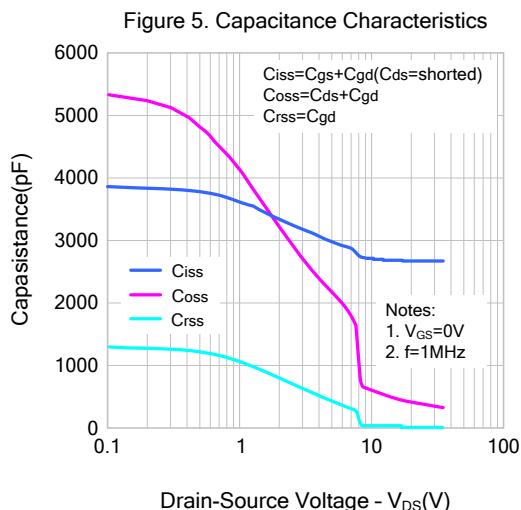
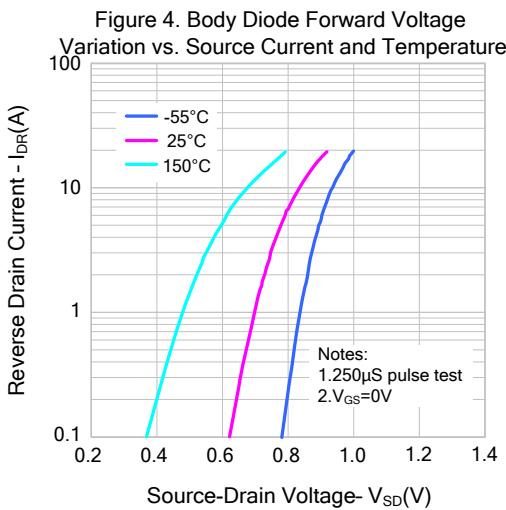
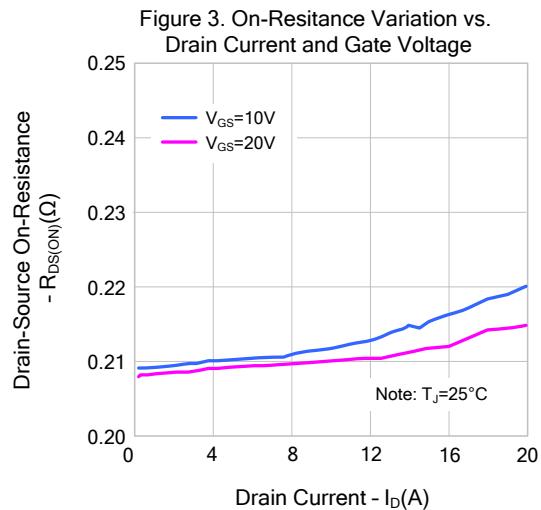
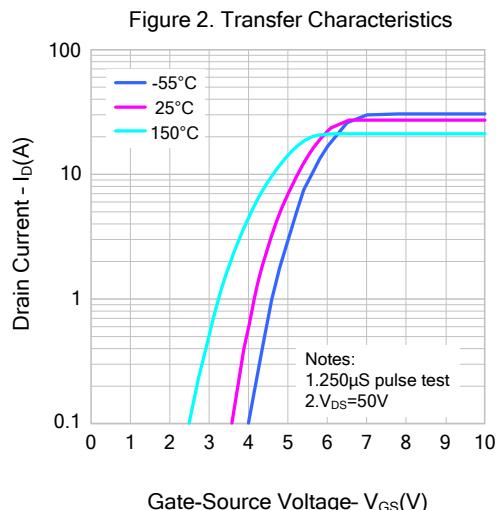
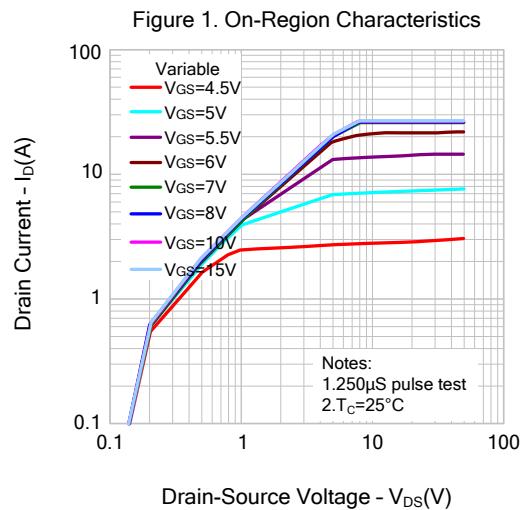
Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I_S	Integral Reverse P-N Junction Diode in the MOSFET	--	--	20.0	A
Pulsed Source Current	I_{SM}		--	--	80.0	
Diode Forward Voltage	V_{SD}	$I_S=20.0\text{A}, V_{GS}=0\text{V}$	--	--	1.4	V
Reverse Recovery Time	T_{rr}	$I_S=20.0\text{A}, V_{GS}=0\text{V},$ $dI/dt=100\text{A}/\mu\text{s}$ (Note 2)	--	570.3	--	ns
Reverse Recovery Charge	Q_{rr}		--	7.35	--	μC

Notes:

1. $L=30\text{mH}, I_{AS}=9.9\text{A}, V_{DD}=50\text{V}, R_G=25\Omega$, starting $T_J=25^\circ\text{C}$;
2. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$;
3. Essentially independent of operating temperature.



TYPICAL CHARACTERISTICS





TYPICAL CHARACTERISTICS(continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

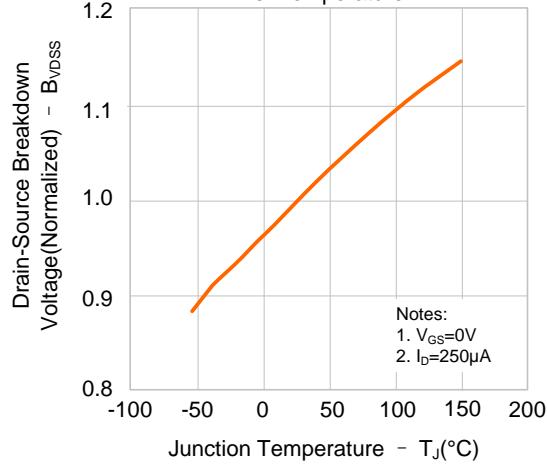


Figure 8. On-resistance Variation vs. Temperature

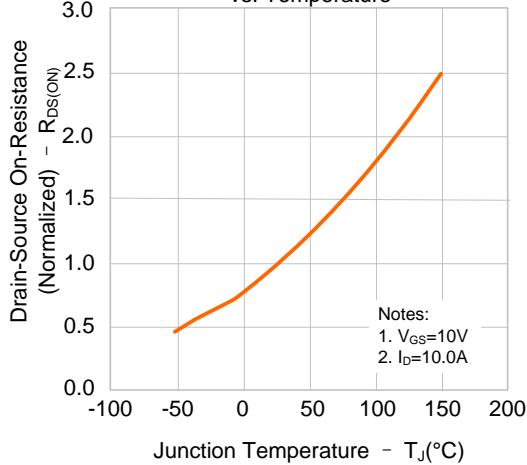


Figure 9-1. Max. Safe Operating Area (SVF20N50F)

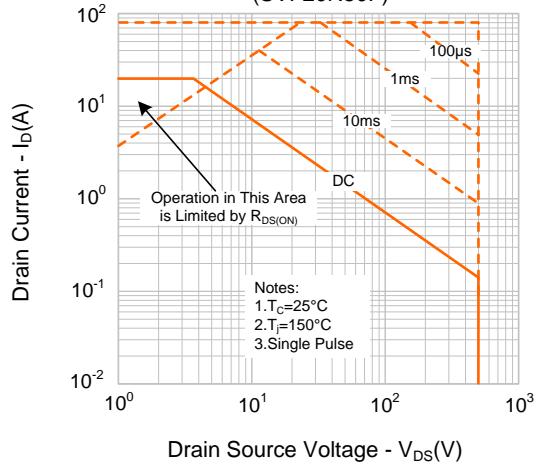


Figure 9-2. Max. Safe Operating Area (SVF20N50PN)

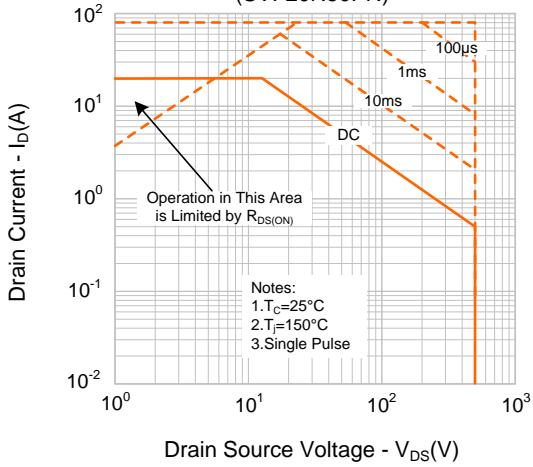
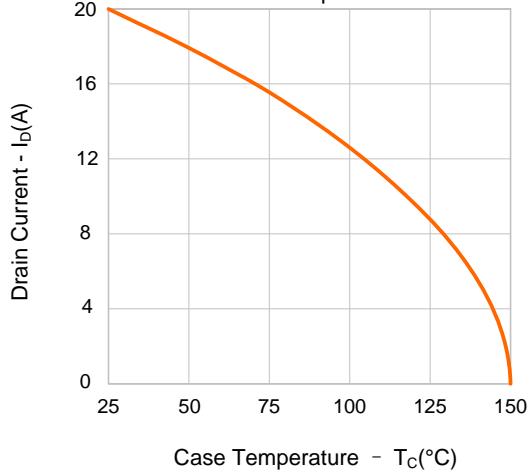


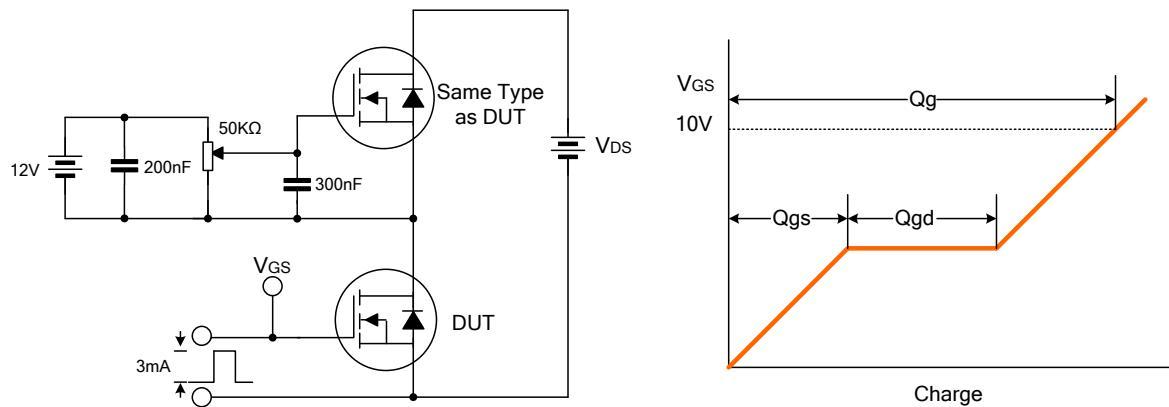
Figure 10. Maximum Drain Current vs. Case Temperature



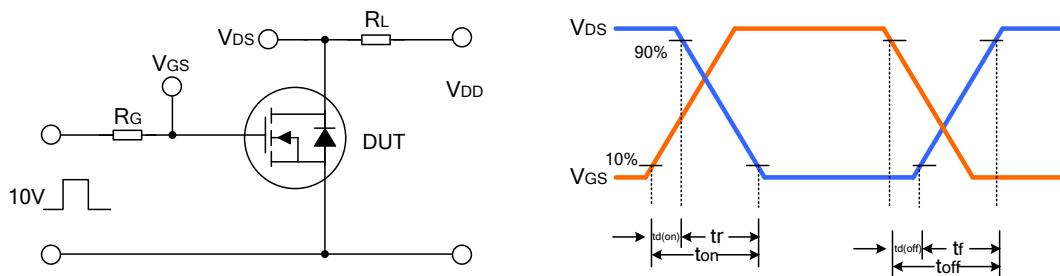


TYPICAL TEST CIRCUIT

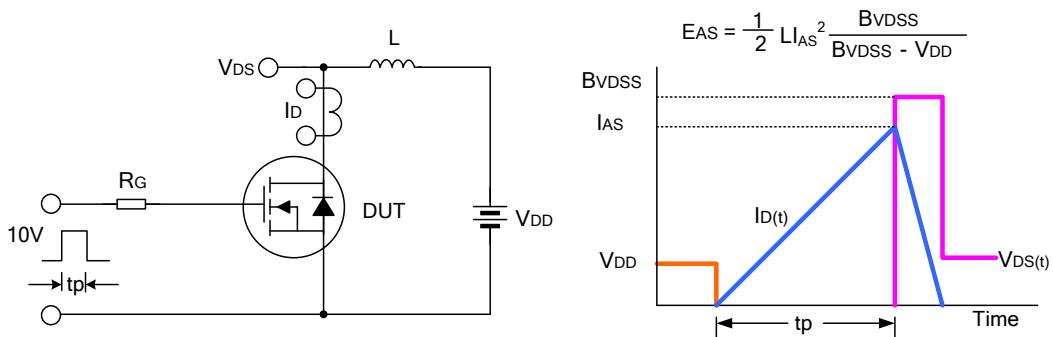
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform



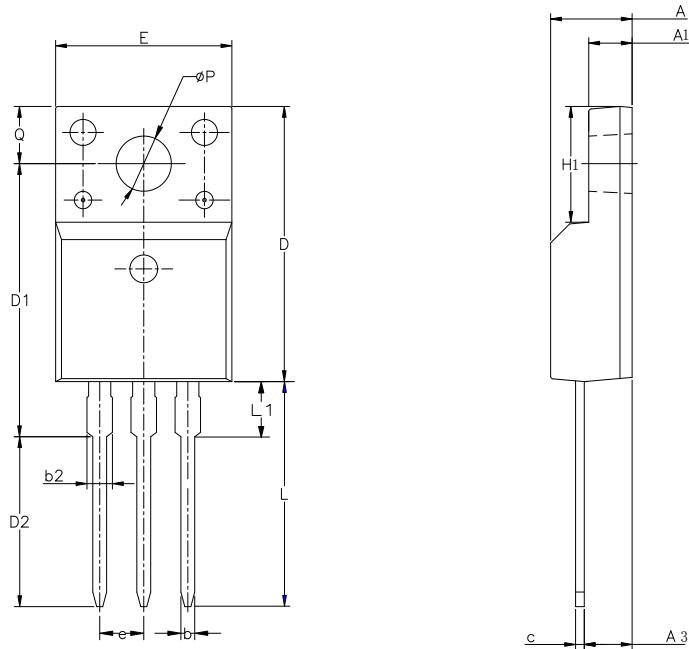
Unclamped Inductive Switching Test Circuit & Waveform



PACKAGE OUTLINE

TO-220F-3L

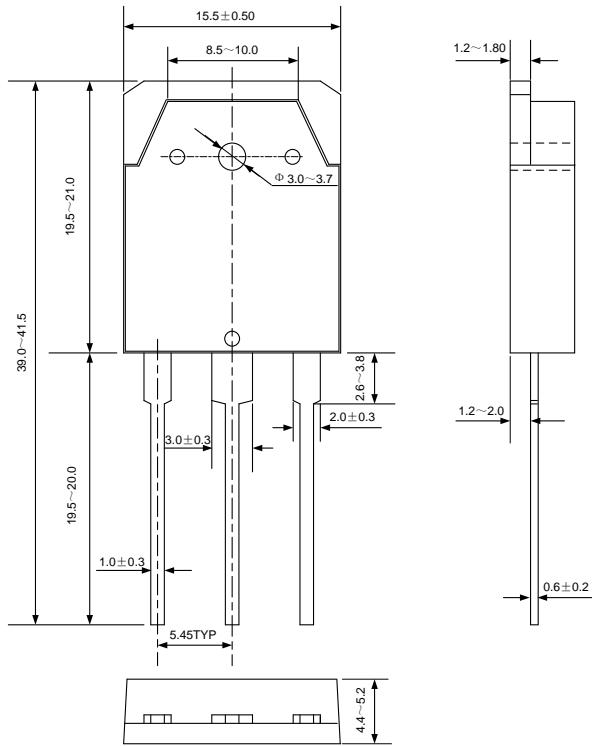
UNIT: mm



SYMBOL	MIN	NOM	MAX
A	4.42	4.70	5.02
A1	2.30	2.54	2.80
A3	2.50	2.76	3.10
b	0.70	0.80	0.90
b2	—	—	1.47
c	0.35	0.50	0.65
D	15.25	15.87	16.25
D1	15.30	15.75	16.30
D2	9.30	9.80	10.30
E	9.73	10.16	10.36
e		2.54BCS	
H1	6.40	6.68	7.00
L	12.48	12.98	13.48
L1	/	/	3.50
øP	3.00	3.18	3.40
Q	3.05	3.30	3.55

TO-3P

UNIT: mm



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Rev.: 1.5 Author: Yin Zi

Revision History:

1. Modify the package information of TO-220F-3L

Rev.: 1.4 Author: Yin Zi

Revision History:

1. Modify the thermal characteristics

Rev.: 1.3 Author: Yin Zi

Revision History:

1. Modify the ordering information

Rev.: 1.2 Author: Zhang Kefeng

Revision History:

1. Change the schematic diagram of MOS

Rev.: 1.1 Author: Zhang Kefeng

Revision History:

1. Add the package of TO-3PN
2. Modify "ELECTRICAL CHARACTERISTICS" and "TYPICAL CHARACTERISTICS"

Rev.: 1.0 Author: Zhang Kefeng

Revision History:

1. Initial release